

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
		09/985,768	BOATENG, KWAME OSEI	
		Examiner	Art Unit	Page 1 of 3
		Vuthe Siek	2825	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	A	US-6,782,501	08-2004	Distler et al.	714/738
	B	US-2002/0099991	07-2002	Distler et al.	714/738
	C	US-			
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Kajihara et al., "COST-EFFECTIVE GENERATION OF MINIMAL TEST SETS FOR STUCK-AT FAULTS IN COMBINATIONAL LOGIC CIRCUITS," IEEE, DEC. 1995, PP. 1496-1504.
	V	Guo et al., "ON IMPROVING STATIC TEST COMPACTION OF SEQUENTIAL CIRCUITS," IEEE, JAN. 3-7, 2001, PP. 111-116.
	W	Pomeranz et al, "STATIC TEST COMPACTION FOR SYNCHRONOUS SEQUENTIAL CIRCUITS BASED ON VECTOR RESTORATION," IEEE, JULY, 1999, PP. 1040-1049.
	X	Pomeranz et al., "VECTOR REPLACEMENT TO IMPROVE STATIC-TEST COMPACTION FOR SYNCHRONOUS SEQUENTIAL CIRCUITS," IEEE, FEB. 2001, PP. 336-342.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)

Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Pomeranz et al., "VERSE: A VECTOR REPLACEMENT PROCEDURE FOR IMPROVING TEST COMPACTION IN SYNCHRONOUS SEQUENTIAL CIRCUITS," IEEE, JAN 7-10, 1999, PP. 1-6.
	V	Higami et al., "TEST SEQUENCE COMPACTION FOR SEQUENTIAL CIRCUITS WITH RESET STATES," IEEE, DEC. 4-6, 2000, PP. 165-170.
	W	Pomeranz et al., "AN APPROACH FOR IMPROVING THE LEVELS OF COMPACTION ACHIEVED BY VECTOR OMISSION," IEEE, NOV. 7-11, 1999, PP. 463-466.
	X	Guo et al., "ON SPEEEDING-UP VECTOR RESTORATION BASED STATIC COMPACTION OF TEST SEQUENCES FRO SEQUENTIAL CIRCUITS," IEEE, DEC. 1998, PP. 467-471.

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.

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	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Hsiao et al., "FAST STATIC COMPACTION ALGORITHMS FOR SEQUENTIAL CIRCUIT TEST VECTORS," IEEE, MARCH 1999, PP. 311-322.
	V	Elizabeth et al., "EFFICIENT TECHNIQUES FOR DYNAMIC TEST SEQUENCE COMPACTION," IEEE, MARCH 1999, PP. 323-330.
	W	
	X	

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Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.